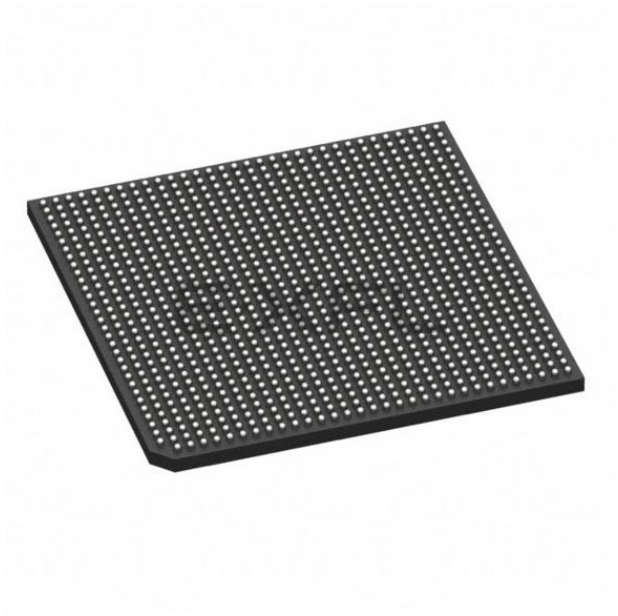

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.067GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	1023-BFBGA, FCBGA
Supplier Device Package	1023-FCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572ecpxarlb

Figure 1 shows the MPC8572E block diagram.

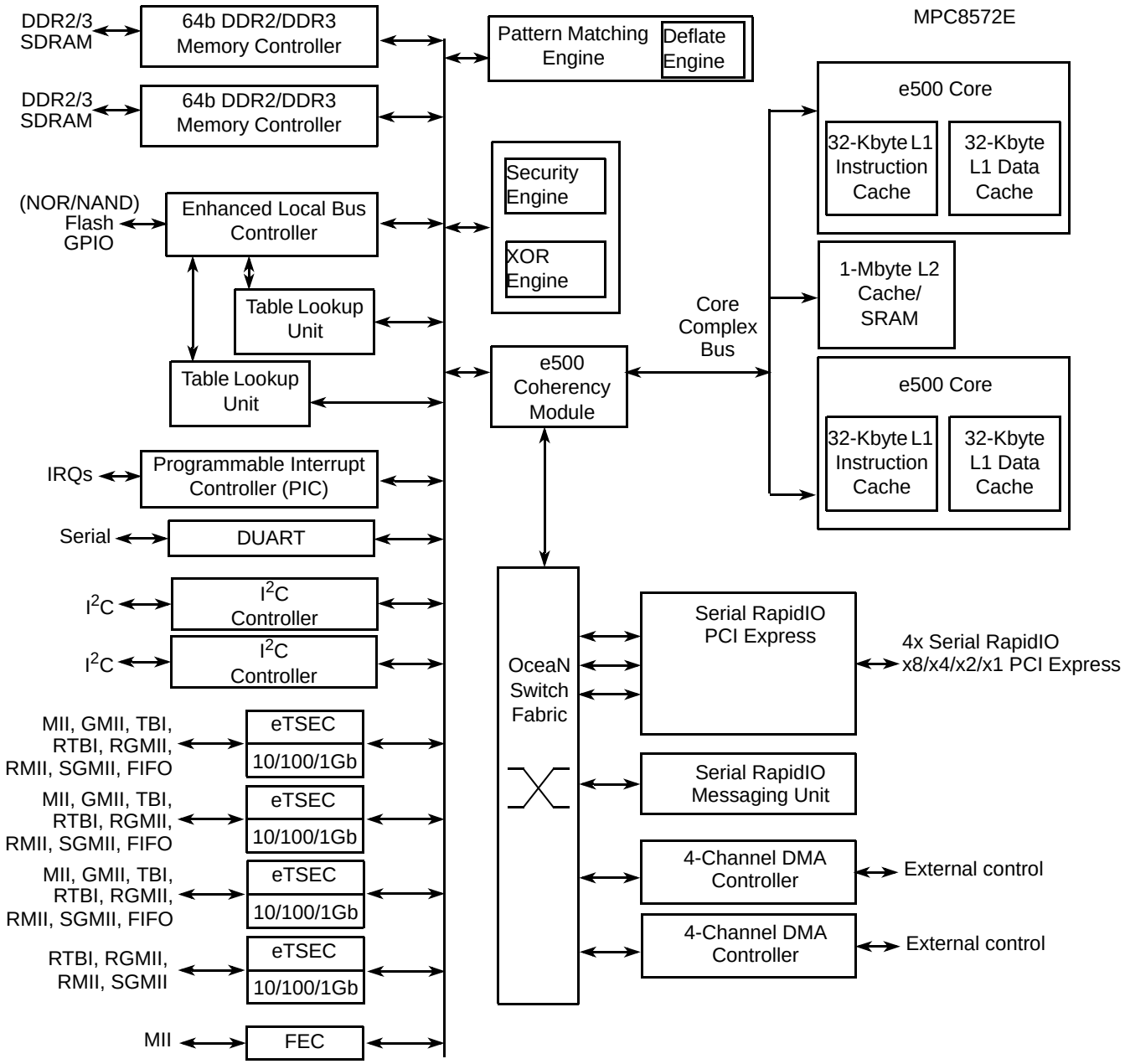
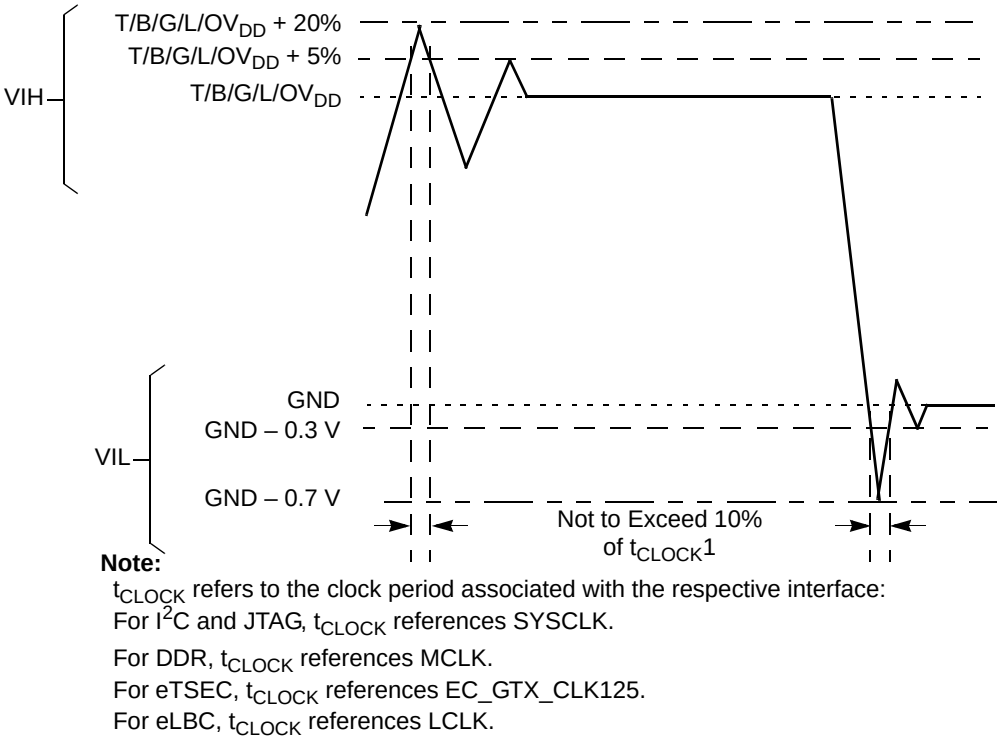


Figure 1. MPC8572E Block Diagram

2 Electrical Characteristics

This section provides the AC and DC electrical specifications for the MPC8572E. The MPC8572E is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

Figure 2 shows the undershoot and overshoot voltages at the interfaces of the MPC8572E.



Note:
t_{CLOCK} refers to the clock period associated with the respective interface:
For I^2C and JTAG, t_{CLOCK} references SYSCLK.
For DDR, t_{CLOCK} references MCLK.
For eTSEC, t_{CLOCK} references EC_GTX_CLK125.
For eLBC, t_{CLOCK} references LCLK.

Figure 2. Overshoot/Undershoot Voltage for $TV_{DD}/BV_{DD}/GV_{DD}/LV_{DD}/OV_{DD}$

The core voltage must always be provided at nominal 1.1 V. (See Table 2 for actual recommended core voltage.) Voltage to the processor interface I/Os are provided through separate sets of supply pins and must be provided at the voltages shown in Table 2. The input voltage threshold scales with respect to the associated I/O supply voltage. TV_{DD}, BV_{DD}, OV_{DD}, and LV_{DD} based receivers are simple CMOS I/O circuits and satisfy appropriate LVCMOS type specifications. The DDR2 and DDR3 SDRAM interface uses differential receivers referenced by the externally supplied $MV_{REF}n$ signal (nominally set to $GV_{DD}/2$) as is appropriate for the SSTL_1.8 electrical signaling standard for DDR2 or 1.5-V electrical signaling for DDR3. The DDR DQS receivers cannot be operated in single-ended fashion. The complement signal must be properly driven and cannot be grounded.

4.3 eTSEC Gigabit Reference Clock Timing

Table 7 provides the eTSEC gigabit reference clocks (EC_GTX_CLK125) AC timing specifications for the MPC8572E.

Table 7. EC_GTX_CLK125 AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3V ± 5% or 2.5V ± 5%

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
EC_GTX_CLK125 frequency	f_{G125}	—	125	—	MHz	—
EC_GTX_CLK125 cycle time	t_{G125}	—	8	—	ns	—
EC_GTX_CLK125 rise and fall time L/TV_{DD}=2.5V L/TV_{DD}=3.3V	t_{G125R}, t_{G125F}	—	—	 0.75 1.0	ns	1
EC_GTX_CLK125 duty cycle GMII, TBI 1000Base-T for RGMII, RTBI	t_{G125H}/t_{G125}	 45 47	—	 55 53	%	2, 3

Notes:

1. Rise and fall times for EC_GTX_CLK125 are measured from 0.5V and 2.0V for L/TV_{DD}=2.5V, and from 0.6V and 2.7V for L/TV_{DD}=3.3V.
2. Timing is guaranteed by design and characterization.
3. EC_GTX_CLK125 is used to generate the GTX clock for the eTSEC transmitter with 2% degradation. EC_GTX_CLK125 duty cycle can be loosened from 47/53% as long as the PHY device can tolerate the duty cycle generated by the TSEC*n*_GTX_CLK. See Section 8.2.6, "RGMII and RTBI AC Timing Specifications," for duty cycle for 10Base-T and 100Base-T reference clock.

4.4 DDR Clock Timing

Table 8 provides the DDR clock (DDRCLK) AC timing specifications for the MPC8572E.

Table 8. DDRCLK AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3V ± 5%.

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
DDRCLK frequency	f_{DDRCLK}	66	—	100	MHz	1
DDRCLK cycle time	t_{DDRCLK}	10.0	—	15.15	ns	—
DDRCLK rise and fall time	t_{KH}, t_{KL}	0.6	1.0	1.2	ns	2
DDRCLK duty cycle	t_{KHK}/t_{DDRCLK}	40	—	60	%	3

Table 9. RESET Initialization Timing Specifications (continued)

PLL config input setup time with stable SYSCLK before $\overline{\text{HRESET}}$ negation	100	—	µs	—
Input setup time for POR configs (other than PLL config) with respect to negation of $\overline{\text{HRESET}}$	4	—	SYSCLKs	1
Input hold time for all POR configs (including PLL config) with respect to negation of $\overline{\text{HRESET}}$	2	—	SYSCLKs	1
Maximum valid-to-high impedance time for actively driven POR configs with respect to negation of $\overline{\text{HRESET}}$	—	5	SYSCLKs	1

Notes:
1. SYSCLK is the primary clock input for the MPC8572E.
2. Reset assertion timing requirements for DDR3 DRAMs may differ.

Table 10 provides the PLL lock times.

Table 10. PLL Lock Times

Parameter/Condition	Symbol	Min	Typical	Max
PLL lock times	—	100	µs	—
Local bus PLL	—	50	µs	—

6 DDR2 and DDR3 SDRAM Controller

This section describes the DC and AC electrical specifications for the DDR2 and DDR3 SDRAM controller interface of the MPC8572E. Note that the required GV_{DD}(typ) voltage is 1.8Vor 1.5 V when interfacing to DDR2 or DDR3 SDRAM, respectively.

6.1 DDR2 and DDR3 SDRAM Interface DC Electrical Characteristics

Table 11 provides the recommended operating conditions for the DDR SDRAM controller of the MPC8572E when interfacing to DDR2 SDRAM.

Table 11. DDR2 SDRAM Interface DC Electrical Characteristics for GV_{DD}(typ) = 1.8 V

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV_{DD}	1.71	1.89	V	1
I/O reference voltage	$MV_{REF}n$	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V_{TT}	$MV_{REF}n - 0.04$	$MV_{REF}n + 0.04$	V	3
Input high voltage	V_{IH}	$MV_{REF}n + 0.125$	$GV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	–0.3	$MV_{REF}n - 0.125$	V	—
Output leakage current	I_{OZ}	–50	50	µA	4
Output high current (V_{OUT} = 1.420 V)	I_{OH}	–13.4	—	mA	—

Table 14 provides the current draw characteristics for $MV_{REF}n$.

Table 14. Current Draw Characteristics for MV_{REF} *n*

Parameter / Condition		Symbol	Min	Max	Unit	Note
Current draw for $MV_{REF}n$	DDR2 SDRAM	$I_{MVREF}n$	—	1500	µA	1
	DDR3 SDRAM			1250		

1. The voltage regulator for $MV_{REF}n$ must be able to supply up to 1500 µA or 1250 uA current for DDR2 or DDR3, respectively.

6.2 DDR2 and DDR3 SDRAM Interface AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR SDRAM controller interface. The DDR controller supports both DDR2 and DDR3 memories. Note that although the minimum data rate for most off-the-shelf DDR3 DIMMs available is 800 MHz, JEDEC specification does allow the DDR3 to run at the data rate as low as 606 MHz. Unless otherwise specified, the AC timing specifications described in this section for DDR3 is applicable for data rate between 606 MHz and 800 MHz, as long as the DC and AC specifications of the DDR3 memory to be used are compliant to both JEDEC specifications as well as the specifications and requirements described in this MPC8572E hardware specifications document.

6.2.1 DDR2 and DDR3 SDRAM Interface Input AC Timing Specifications

Table 15, Table 16, and Table 17 provide the input AC timing specifications for the DDR controller when interfacing to DDR2 and DDR3 SDRAM.

Table 15. DDR2 SDRAM Interface Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions with GV_{DD} of 1.8 V ± 5%

Parameter		Symbol	Min	Max	Unit	Notes
AC input low voltage	>=667 MHz	V_{ILAC}	—	$MV_{REF}n$ – 0.20	V	—
	<= 533 MHz		—	$MV_{REF}n$ – 0.25		
AC input high voltage	>=667 MHz	V_{IHAC}	$MV_{REF}n$ + 0.20	—	V	—
—	<= 533 MHz		$MV_{REF}n$ + 0.25	—		

Table 16. DDR3 SDRAM Interface Input AC Timing Specifications for 1.5-V Interface

At recommended operating conditions with GV_{DD} of 1.5 V ± 5%. DDR3 data rate is between 606 MHz and 800 MHz.

Parameter	Symbol	Min	Max	Unit	Notes
AC input low voltage	V_{ILAC}	—	$MV_{REF}n$ – 0.175	V	—
AC input high voltage	V_{IHAC}	$MV_{REF}n$ + 0.175	—	V	—

Table 18. DDR2 and DDR3 SDRAM Interface Output AC Timing Specifications (continued)

At recommended operating conditions with GV_{DD} of 1.8 V ± 5% for DDR2 or 1.5 V ± 5% for DDR3.

Parameter	Symbol [1]	Min	Max	Unit	Notes
800 MHz		0.917	—		
667 MHz		1.10	—		
533 MHz		1.48	—		
400 MHz		1.95	—		
ADDR/CMD output hold with respect to MCK	t_{DDKHAX}			ns	3
800 MHz		0.917	—		
667 MHz		1.10	—		
533 MHz		1.48	—		
400 MHz		1.95	—		
$\overline{\text{MCS}}$[n] output setup with respect to MCK	t_{DDKHCS}			ns	3
800 MHz		0.917	—		
667 MHz		1.10	—		
533 MHz		1.48	—		
400 MHz	t_{DDKHCS}	1.95	—	ns	3
$\overline{\text{MCS}}$[n] output hold with respect to MCK	t_{DDKHCX}			ns	3
800 MHz		0.917	—		
667 MHz		1.10	—		
533 MHz		1.48	—		
400 MHz		1.95	—		
MCK to MDQS Skew	t_{DDKHMH}			ns	4
800 MHz		–0.375	0.375		
<= 667 MHz		–0.6	0.6		
MDQ/MECC/MDM output setup with respect to MDQS	t_{DDKHDS}, t_{DDKLDS}			ps	5
800 MHz		375	—		
667 MHz		450	—		
533 MHz		538	—		
400 MHz		700	—		
MDQ/MECC/MDM output hold with respect to MDQS	t_{DDKHDX}, t_{DDKLDX}			ps	5
800 MHz		375	—		
667 MHz		450	—		

Figure 14 shows the MII receive AC timing diagram.

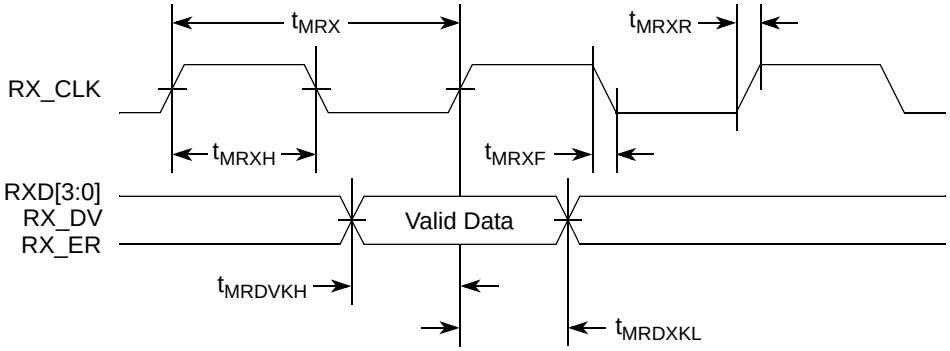


Figure 14. MII Receive AC Timing Diagram

8.2.4 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

8.2.4.1 TBI Transmit AC Timing Specifications

Table 31 provides the TBI transmit AC timing specifications.

Table 31. TBI Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TCG[9:0] setup time GTX_CLK going high	t_{TTKHDV}	2.0	—	—	ns
TCG[9:0] hold time from GTX_CLK going high	t_{TTKHDX}	1.0	—	—	ns
GTX_CLK rise (20%–80%)	t_{TTXR}[2]	—	—	1.0	ns
GTX_CLK fall time (80%–20%)	t_{TTXF}[2]	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.

Figure 15 shows the TBI transmit AC timing diagram.

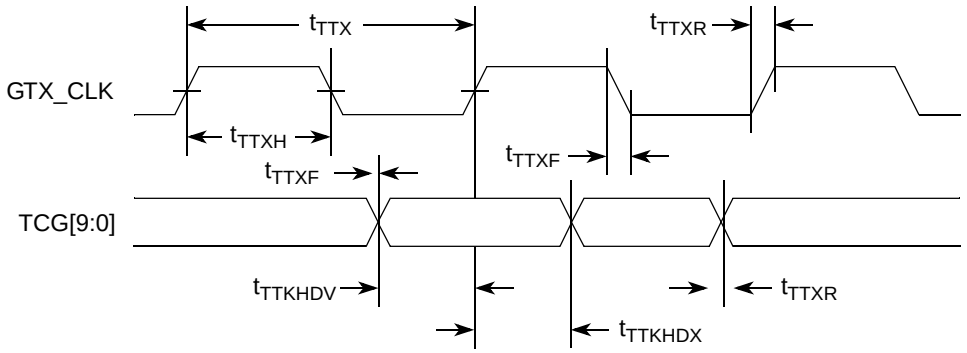


Figure 15. TBI Transmit AC Timing Diagram

8.2.4.2 TBI Receive AC Timing Specifications

Table 32 provides the TBI receive AC timing specifications.

Table 32. TBI Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition [3]	Symbol [1]	Min	Typ	Max	Unit
Clock period for TBI Receive Clock 0, 1	t_{TRX}	—	16.0	—	ns
Skew for TBI Receive Clock 0, 1	t_{SKTRX}	7.5	—	8.5	ns
Duty cycle for TBI Receive Clock 0, 1	t_{TRXH}/t_{TRX}	40	—	60	%
RCG[9:0] setup time to rising edge of TBI Receive Clock 0, 1	t_{TRDVKH}	2.5	—	—	ns
RCG[9:0] hold time to rising edge of TBI Receive Clock 0, 1	t_{TRDXKH}	1.5	—	—	ns
Clock rise time (20%-80%) for TBI Receive Clock 0, 1	t_{TRXR} [2]	0.7	—	2.4	ns
Clock fall time (80%-20%) for TBI Receive Clock 0, 1	t_{TRXF} [2]	0.7	—	2.4	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (TRX).
2. Guaranteed by design.
3. The signals “TBI Receive Clock 0” and “TBI Receive Clock 1” refer to TSECn_RX_CLK and TSECn_TX_CLK pins respectively. These two clock signals are also referred as PMA_RX_CLK[0:1].

Table 35. RMII Transmit AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TSECn_TX_CLK to RMII data TXD[1:0], TX_EN delay	t_{RMTDX}	1.0	—	10.0	ns

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 19 shows the RMII transmit AC timing diagram.

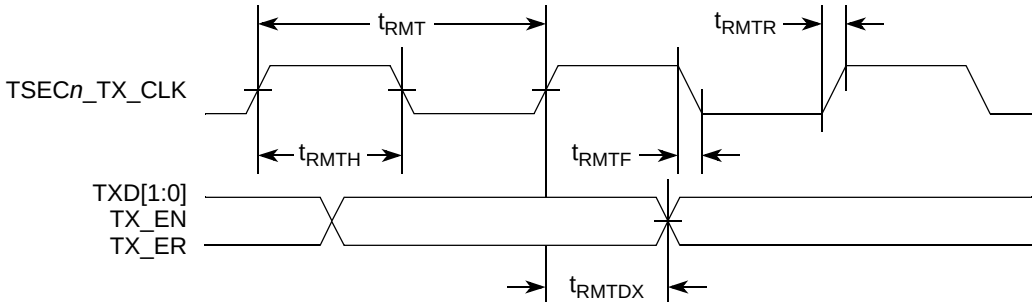


Figure 19. RMII Transmit AC Timing Diagram

8.2.7.2 RMII Receive AC Timing Specifications

Table 36 shows the RMII receive AC timing specifications.

Table 36. RMII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
TSECn_TX_CLK clock period	t_{RMR}	15.0	20.0	25.0	ns
TSECn_TX_CLK duty cycle	t_{RMRH}	35	50	65	%
TSECn_TX_CLK peak-to-peak jitter	t_{RMRJ}	—	—	250	ps
Rise time TSECn_TX_CLK (20%–80%)	t_{RMRR}	1.0	—	2.0	ns
Fall time TSECn_TX_CLK (80%–20%)	t_{RMRF}	1.0	—	2.0	ns
RXD[1:0], CRS_DV, RX_ER setup time to TSECn_TX_CLK rising edge	t_{RMRDV}	4.0	—	—	ns

8.4 eTSEC IEEE Std 1588™ AC Specifications

Figure 26 shows the data and command output timing diagram.

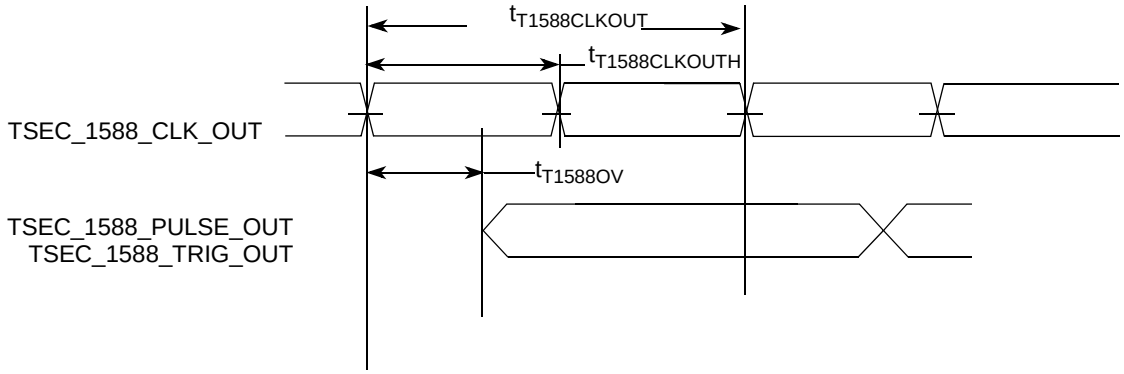


Figure 26. eTSEC IEEE 1588 Output AC Timing

1 The output delay is count starting rising edge if $t_{T1588CLKOUT}$ is non-inverting. Otherwise, it is count starting falling edge.

Figure 27 shows the data and command input timing diagram.

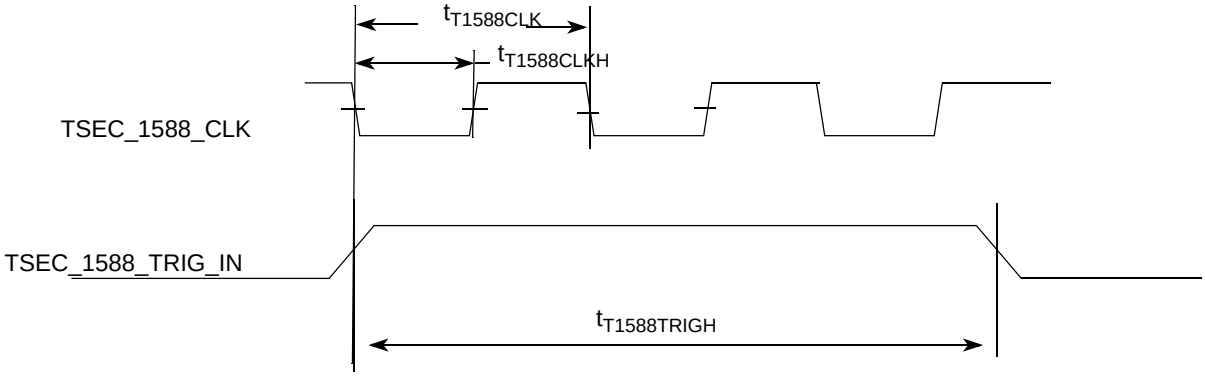


Figure 27. eTSEC IEEE 1588 Input AC timing

Table 42 provides the IEEE 1588 AC timing specifications.

Table 42. eTSEC IEEE 1588 AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Note
TSEC_1588_CLK clock period	$t_{T1588CLK}$	3.3	—	T_{TX_CLK}*9	ns	1
TSEC_1588_CLK duty cycle	$t_{T1588CLKH}$ /$t_{T1588CLK}$	40	50	60	%	—
TSEC_1588_CLK peak-to-peak jitter	$t_{T1588CLKINJ}$	—	—	250	ps	—
Rise time eTSEC_1588_CLK (20%–80%)	$t_{T1588CLKINR}$	1.0	—	2.0	ns	—
Fall time eTSEC_1588_CLK (80%–20%)	$t_{T1588CLKINF}$	1.0	—	2.0	ns	—
TSEC_1588_CLK_OUT clock period	$t_{T1588CLKOUT}$	2*$t_{T1588CLK}$	—	—	ns	—

Table 51. Local Bus General Timing Parameters (BV_{DD} = 1.8 V DC)—PLL Enabled (continued)

At recommended operating conditions with BV_{DD} of 1.8 V ± 5% (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
$\overline{\text{LGTA}}$/LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.1	—	ns	3, 4
LALE output negation to high impedance for LAD/LDP (LATCH hold time)	t_{LBOTOT}	1.2	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	3.2	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	3.2	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	3.2	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	3.2	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.9	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.9	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.6	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.6	ns	5

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 1.8-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Figure 29 provides the AC test load for the local bus.

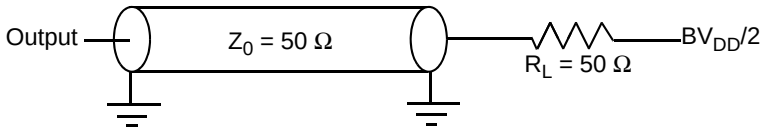


Figure 29. Local Bus AC Test Load

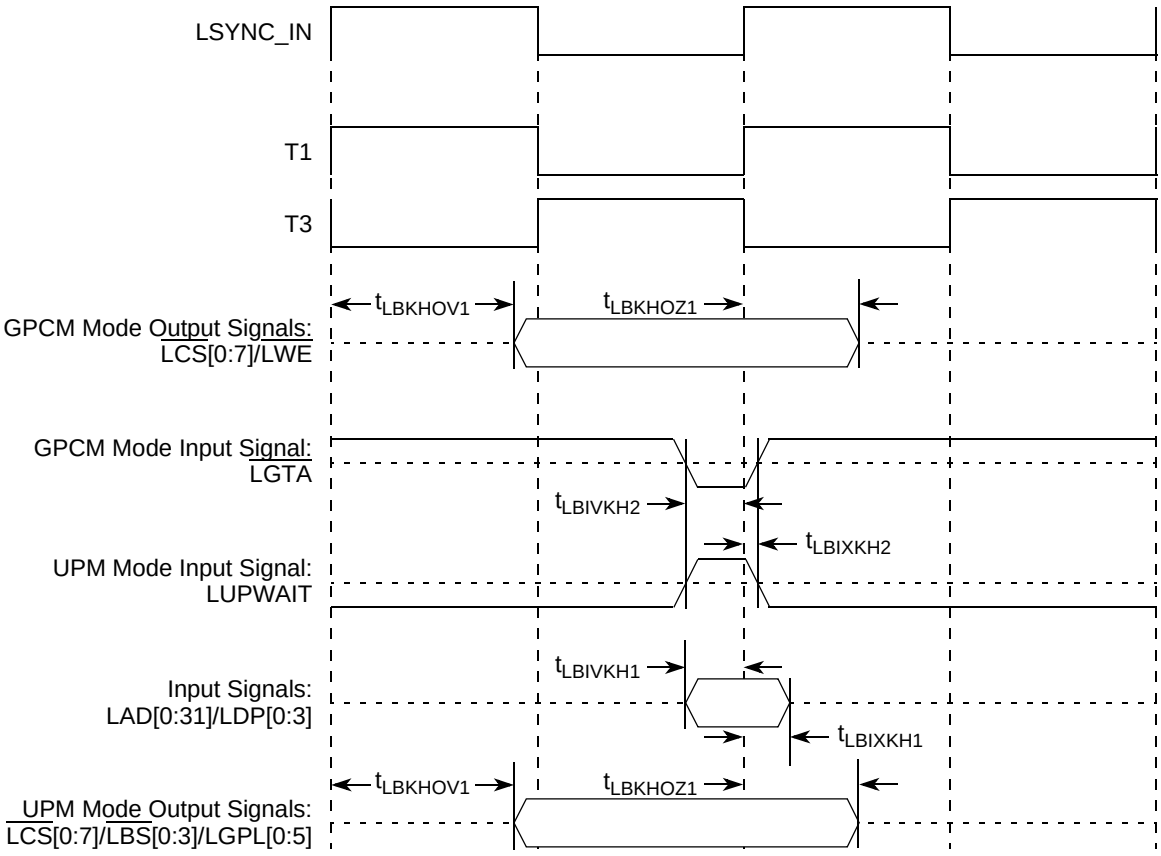


Figure 32. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (PLL Enabled)

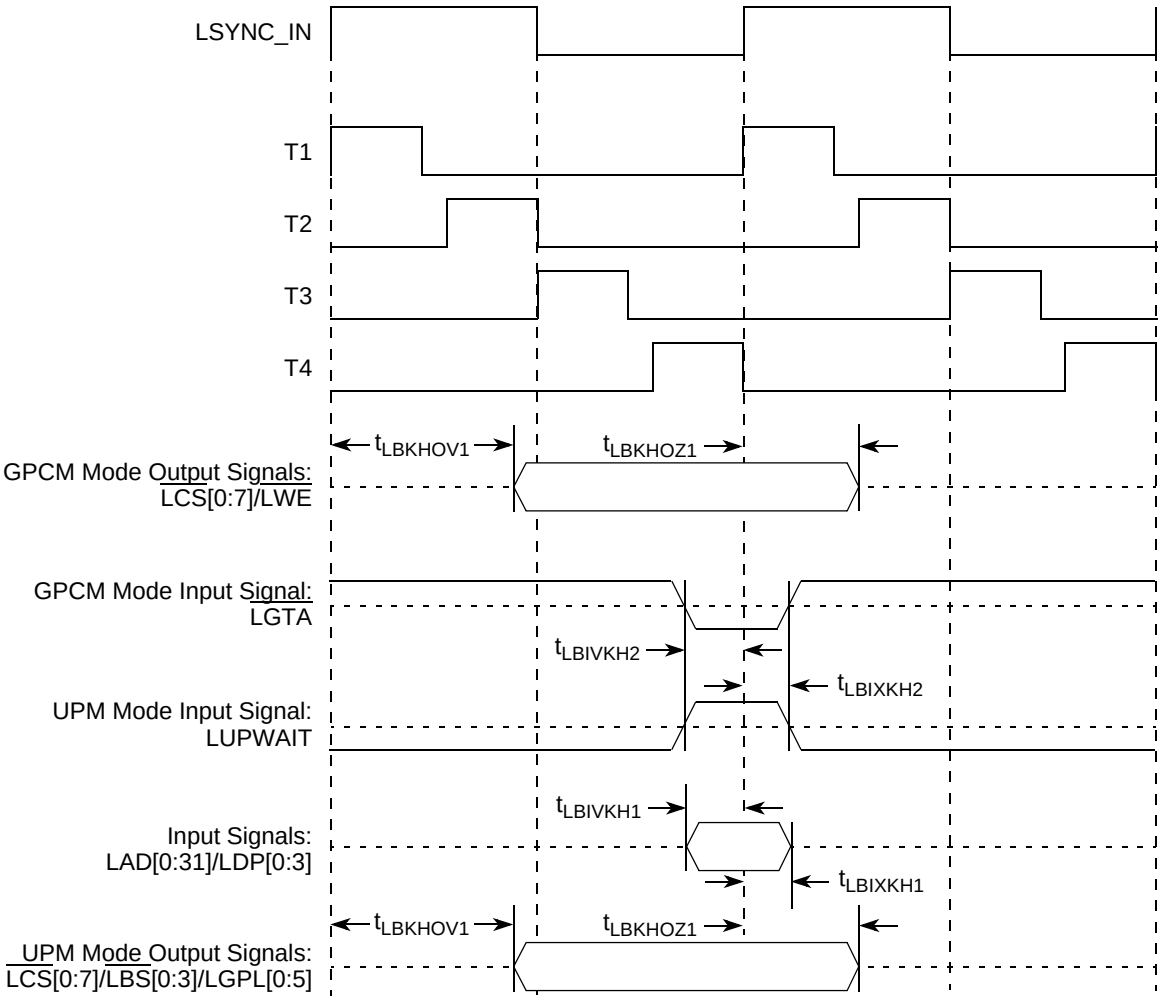


Figure 34. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 8 or 16 (PLL Enabled)

17.1 DC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK

For more information, see Section 15.2, “SerDes Reference Clocks.”

17.2 AC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK

Figure 64lists the AC requirements.

Table 64. SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ AC Requirements

Symbol	Parameter Description	Min	Typical	Max	Units	Comments
t_{REF}	REFCLK cycle time	—	10(8)	—	ns	8 ns applies only to serial RapidIO with 125-MHz reference clock
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles	—	—	80	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	–40	—	40	ps	—

17.3 Equalization

With the use of high speed serial links, the interconnect media causes degradation of the signal at the receiver. Effects such as Inter-Symbol Interference (ISI) or data dependent jitter are produced. This loss can be large enough to degrade the eye opening at the receiver beyond what is allowed in the specification. To negate a portion of these effects, equalization can be used. The most common equalization techniques that can be used are as follows:

- A passive high pass filter network placed at the receiver. This is often referred to as passive equalization.
- The use of active circuits in the receiver. This is often referred to as adaptive equalization.

17.4 Explanatory Note on Transmitter and Receiver Specifications

AC electrical specifications are given for transmitter and receiver. Long run and short run interfaces at three baud rates (a total of six cases) are described.

The parameters for the AC electrical specifications are guided by the XAUI electrical interface specified in Clause 47 of IEEE 802.3ae-2002.

XAUI has similar application goals to serial RapidIO, as described in Section 8.1, “Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1000 Mbps)—FIFO/GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics.” The goal of this standard is that electrical designs for Serial RapidIO can reuse electrical designs for XAUI, suitably modified for applications at the baud intervals and reaches described herein.

link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than 10^{-12}. The eye pattern shall be measured with AC coupling and the compliance template centered at 0 Volts differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100 Ω resistive +/– 5% differential to 2.5 GHz.

17.8.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (Baud Frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter Test Pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 Volts differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

17.8.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100 Ω resistive +/– 5% differential to 2.5 GHz.

17.8.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in Section 17.6, “Receiver Specifications,” and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in Figure 60 and Table 75. Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in Section 17.6, “Receiver Specifications,” is then added to the signal and the test load is replaced by the receiver being tested.

18 Package Description

This section describes package parameters, pin assignments, and dimensions.

18.1 Package Parameters for the MPC8572E FC-PBGA

The package parameters are as provided in the following list. The package type is 33 mm × 33 mm, 1023 flip chip plastic ball grid array (FC-PBGA).

Package outline	33 mm × 33 mm
Interconnects	1023
Ball Pitch	1 mm
Ball Diameter (Typical)	0.6 mm
Solder Balls	63% Sn
	37% Pb
Solder Balls (Lead-Free)	96.5% Sn
	3.5% Ag

Table 79. CCB Clock Ratio

Binary Value of LA[29:31] Signals	CCB:SYSCLK Ratio
000	4:1
001	5:1
010	6:1
011	8:1
100	10:1
101	12:1
110	Reserved
111	Reserved

19.3 e500 Core PLL Ratio

The clock speed for each e500 core can be configured differently, determined by the values of various signals at power up.

Table 80 describes the clock ratio between e500 Core0 and the e500 core complex bus (CCB). This ratio is determined by the binary value of LBCTL, LALE and LGPL2/$\overline{\text{LOE}}$/$\overline{\text{LFRE}}$ at power up, as shown in Table 80.

Table 80. e500 Core0 to CCB Clock Ratio

Binary Value of LBCTL, LALE, LGPL2/LOE/LFRE Signals	e500 Core0:CCB Clock Ratio	Binary Value of LBCTL, LALE, LGPL2/LOE/LFRE Signals	e500 Core0:CCB Clock Ratio
000	Reserved	100	2:1
001	Reserved	101	5:2 (2.5:1)
010	Reserved	110	3:1
011	3:2 (1.5:1)	111	7:2 (3.5:1)

21 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8572E.

21.1 System Clocking

The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in Section 19.2, "CCB/SYSCLK PLL Ratio." The MPC8572E includes seven PLLs, with the following functions:

- Two core PLLs have ratios that are individually configurable. Each e500 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e500 core clock and the platform clock is selected using the e500 PLL ratio configuration bits as described in Section 19.3, "e500 Core PLL Ratio."
- The DDR complex PLL generates the clocking for the DDR controllers.
- The local bus PLL generates the clock for the local bus.
- The PLL for the SerDes1 module is used for PCI Express and Serial Rapid IO interfaces.
- The PLL for the SerDes2 module is used for the SGMII interface.

21.2 Power Supply Design

21.2.1 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins (AV_{DD}_PLAT, AV_{DD}_CORE0, AV_{DD}_CORE1, AV_{DD}_DDR, AV_{DD}_LBIU, AV_{DD}_SRDS1 and AV_{DD}_SRDS2 respectively). The AV_{DD} level should always be equivalent to V_{DD}, and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in Figure 62, one to each of the AV_{DD} pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of the 1023 FC-PBGA footprint, without the inductance of vias.

21.10.3 SerDes 2 Interface (SGMII) Entirely Unused

If the high-speed SerDes 2 interface (SGMII) is not used at all, the unused pin should be terminated as described in this section.

The following pins must be left unconnected (float):

- SD2_TX[3:0]
- $\overline{\text{SD2\_TX}}$[3:0]
- Reserved pins: AF26, AF27

The following pins must be connected to XGND_SRDS2:

- SD2_RX[3:0]
- $\overline{\text{SD2\_RX}}$[3:0]
- SD2_REF_CLK
- $\overline{\text{SD2\_REF\_CLK}}$

The POR configuration pin cfg_srds_sgmii_en on $\overline{\text{UART\_RTS}}$[1] can be used to power down SerDes 2 block for power saving. Note that both SVDD_SRDS2 and XVDD_SRDS2 must remain powered.

21.10.4 SerDes 2 Interface (SGMII) Partly Unused

If only part of the high speed SerDes 2 interface (SGMII) pins are used, the remaining high-speed serial I/O pins should be terminated as described in this section.

The following pins must be left unconnected (float):

- SD2_TX[3:0]
- $\overline{\text{SD2\_TX}}$[3:0]
- Reserved pins: AF26, AF27

The following pins must be connected to XGND_SRDS2:

- SD2_RX[3:0]
- $\overline{\text{SD2\_RX}}$[3:0]

[3] Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by part number specifications may support other maximum core frequencies.

22.2 Part Marking

Parts are marked as the example shown in Figure 67.

FC-PBGA

Notes:
MMMMMM is the 6-digit mask number.
ATWLYYWW is the traceability code.
CCCCC is the country of assembly. This space is left blank if parts are assembled in the United States.

Figure 67. Part Marking for FC-PBGA Device

Table 89 explains line four of Figure 67.

Table 89. Meaning of Last Line of Part Marking

Digit	Description
A	Assembly Site E Oak Hill Q KLM
WL	Lot number
YY	Year assembled
WW	Work week assembled

23 Document Revision History

Table 90 provides a revision history for the MPC8572E hardware specification.

Table 90. Document Revision History

Rev. Number	Date	Substantive Change(s)
7	03/2016	• Updated Section 22.2, “Part Marking,” changed the five-digit mask number to six digits.